**Instrument specification for the pXRF device.**

This instrument is equipped with a Rhodium target X-Ray tube with a maximum voltage of 30μA at 40kV (15μA at 15kV) and Silicon Drift Detector (SDD). It contains a high-resolution, Peltier cooled, Silicon PIN (Si-PIN) diode detector. The instrument is factory-calibrated, and it was used with the following settings suggested by the factory for the analysis of copper alloys: 40kV voltage beam, 10μA current range, filter 1(Al-300um/Ti-25um). Initially the calibration file “Cu1.CFZ” provided by the factory was used